

**Search Notes**

Application/Control No.

10/693,744

Examiner

John Kreck

Applicant(s)/Patent under  
Reexamination

BAI ET AL.

Art Unit

3673

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
text search attached	12/21/2005	JK